



Microelectronics Test Engineering DVD Lecture Series

Presented by:
University of New Mexico
&
Soft Test Inc.

Soft Test has partnered with the University of New Mexico to offer a comprehensive lecture series that covers a wide range of topics associated with semiconductor test. The University of New Mexico invited thirteen experts to give a total of 30 lectures associated with Test Engineering and Semiconductor Test. The goal was to fill a gap in instruction at the university level and expose students to the thoughts from leading practitioners in the field. These lectures provide a wealth of practical information and insight into current semiconductor issues.

Each guest lecturer is currently practicing test engineering in industry and offers a unique view based upon their actual experience. The series addresses several major subject areas: ATE Testers and Digital Test related topics, Defect Based Testing, and Mixed Signal Testing.

Each of the 30 lectures is approximately 75 minutes long, total lecture time is approximately 37.5 hours. All lectures are available in their entirety on DVD.

The lectures were presented at the UNM and the audience consisted of local UNM students, engineers from the area (Intel, Sandia Labs, Los Alamos Labs), and a nation wide audience from the National Technology University (NTU).

You can purchase the entire Lecture Series Set (30) lectures for **\$3,995** or they are offered in sets of 3 lectures per DVD, priced at **\$500 per DVD**. Discounts are offered for purchases of 3 or more individual DVDs.

The Power Point notes used in the lectures are included with your purchase, and the associated reference books *Fundamentals of Digital Semiconductor Test* and *Fundamentals of Mixed Signal Testing* are also available on the Soft Test web site www-soft-test.com.

Visit our web site to view video samples of each lecture.



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DVD	Lecture	Topics	Presenter
DVD # 1	1	Introduction to Test & Test Economics	Chuck Hawkins - UNM
	2	Economics of Test	Chuck Hawkins - UNM
	3	Test Basics: Function, Fault, and Defect-Based Testing	Chuck Hawkins - UNM
DVD # 2	4	Introduction to Automated Test Equipment - ATE	Chuck Hawkins - UNM
	5	Test Types: Device Specs and DC Opens & Shorts	Guy Perry - Soft Test
	6	Test Types: DC Parameters	Guy Perry - Soft Test
DVD # 3	7	Test Types: Functional Testing	Chris Nelson - Intel
	8	Test Types: AC Parameters	Guy Perry - Soft Test
	9	Design for Testability (DFT)	Chuck Hawkins - UNM
DVD # 4	10	CMOS Defect-Based Test	Anne Gattiker - IMB
	11	Memory Test	Rob Aitken - Artisan
	12	Test Cost Reduction with DFT	Gordon Robinson
DVD # 5	13	Hardware Capabilities	Burnie West - Credence
	14	Wafer Testing Technology	Bill Mann
	15	Test Vector & Program Development	Laura Suriano - Intel
DVD # 6	16	Memory Test	Rob Aitken - Artisan
	17	Board and System Test I	Gordon Robinson
	18	Board and System Test II	Gordon Robinson



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DVD # 7	19	Tester ATE – Past, Present, Future	Bob Huston
	20	IP and SoC Test Basics	Al Crouch - Inovys
	21	IP and SoC Test Basics	Al Crouch - Inovys
DVD # 8	22	IP and SoC Test Basics	Al Crouch - Inovys
	23	Analog & Mixed Signal Testing I	Peter Lindholm - Consultant
	24	Analog & Mixed Signal Testing III	Greg Donohoe - UNM
DVD # 9	25	Analog & Mixed Signal Testing IV	Greg Donohoe - UNM
	26	Leading Edge of Wafer Test Technology	Bill Mann
	27	Analog & Mixed Signal Testing II	Peter Lindholm
DVD # 10	28	Analog & Mixed Signal Testing V	Peter Lindholm
	29	Analog & Mixed Signal Testing VI	Peter Lindholm
	30	Putting TE Feet to the Business: A Practical Perspective	Gene Hnatek - Qualcomm

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Two books were used with the lecture series and provide additional information. The associated reference books are:

Fundamentals of Digital Semiconductor Test

Fundamentals of Mixed Signal Testing

Order on-line at www.soft-test.com